

<p>FORM PTO 1449 (modified)</p> <p>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p>LIST OF REFERENCES CITED BY APPLICANT(S) (use several sheets if necessary)</p> <p>O T P JAN 10 2003 13</p>			ATTY DOCKET NO. 00862.022499.		APPLICATION NO. 10/059,171		
			APPLICANT TAKAO YONEHARA, et al.				
			FILING DATE January 31, 2002		GROUP 287+ 2813		
U.S. PATENT DOCUMENTS							
EXAMINER INTELLIGENT PATENT OFFICE	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TW	6,075,280	06/13/00	Yung et al.		257	620	
	6,136,668	10/24/00	Tamaki, et al.		438	462	
	6,186,384	02/13/01	Sawada		225	2	
	6,465,329	10/15/02	Glenn		438	462	
	2002/0076904	06/20/02	Imler		438	462	
TIU	2002/0100941	08/01/02	Yonehara, et al.		257	359	
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION YES/NO OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

FORM PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE AUG 19 2002 PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00862.022499	APPLICATION NO. 10/059,171		
				APPLICANT TAKAO YONEHARA, et al.			
FILING DATE January 31, 2002				GROUP 2813 2874			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>TW</i>		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
		6,222,513	03/10/1998	Howard, et al.	345	84	
		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
		6,331,208	12/18/2001	Nishida, et al.	117	89	
		6,342,433	01/29/2002	Ohmi, et al.	438	455	
<i>TW</i>		6,382,292	05/07/2002	Ohmi, et al.	156	584	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO OR ABSTRACT
<i>TW</i>	EP	1 122 794	08/08/2001	Europe			
	EP	858 110	08/12/1998	Europe			
	EP	849 788	06/24/1998	Europe			
<i>TW</i>	JP	11-316397	11/16/1999	Japan	G02F		Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>TW</i>		Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7.					
EXAMINER <i>Theresa</i>		DATE CONSIDERED 8/30/04					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

ATTY DOCKET NO.
00862.022499APPLICATION NO.
Not Yet Assigned

APPLICANT

Takao Yonehara, et al.

FILING DATE

1-31-02
Currently herewithGROUP 2813
NL Not Yet Assigned

1059171

U.S. 10/059171

01/31/02

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TM	5,206,749	4/27/93	Zavracky et al.	359	59	
	5,256,562	10/26/93	Vu et al.	437	86	
	5,811,348	9/22/98	Matsushita, et al.	438	455	
	6,107,213	8/22/00	Tayanaka, et al.	438	762	
	5,985,742	11/16/99	Henley, et al.	438	515	
TM	5,856,229	1/5/99	Sakaguchi, et al.	438	406	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
TM	9-312349	12/2/97	Japan			Abstract
TM	886 300	12/23/98	EP			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

Drazen

DATE CONSIDERED

8/30/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1